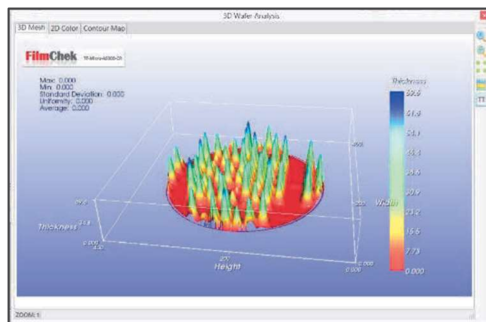
CXsemi

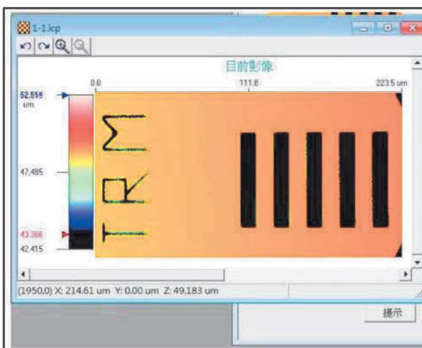
承湘科技股份有限公司

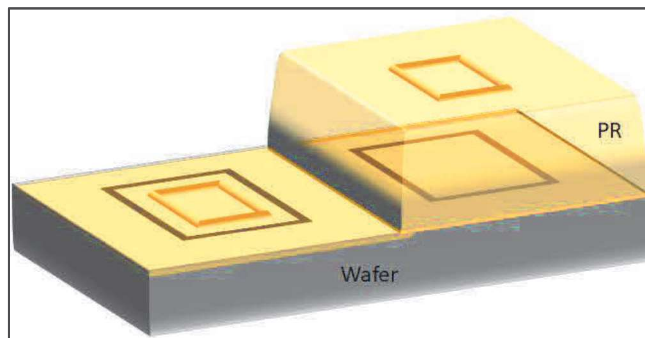
Customize Metrology Tool

Fulfill all your needs with limited budget

- **Filmchek**: Film Thickness, Wafer Thickness, TSV
- **White Light Interferometers**: Step High, 3D Profile, Roughness
- **Opti Profiler**: Wafer Warpage, Stress, Surface Protrusion Defect
- **Overlay**: Pattern Shift, Critical Dimension
- **ADI/AEI**: Macro (Front/Back side), Micro inspection, Surface scan







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